

<b>Notice of References Cited</b>	Application/Control No. 10/086,825	Applicant(s)/Patent Under Reexamination LEE, YOU-SUB	
	Examiner DAVID E HARVEY	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,969,046	11-1990	Sugimoto et al.	348/839
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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